Structured Electronic Design

Analysis and budgeting of biasing errors

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Modeling and analysis of biasing errors

 Worst-case analysis Too pessimistic; results in too tight error budgets
Monte-Carlo analysis Only numeric; not useful for error budgeting
Symbolic statistical analysis Too complex; PDF of the sum of two random variables is found from the convolution of the PDFs of these random variables
Monte-Carlo analysis DC values

Circuit with uncorrelated device tolerances:



Equivalent circuit using the above approximations:



4. Simplified symbolic statistical analysis
Has been implemented in SLiCAP as
DC variance analysis

Simplifications: $\frac{1}{1+\delta} \approx 1 - \delta; \ \delta \ll 1$ $(1+\delta)(1+\epsilon) \approx 1 + \delta + \epsilon; \ \delta \ll 1, \epsilon \ll 1$ SLICAP replaces resistor tolerances

SLiCAP replaces resistor tolerances with error currents

Calculation of the variance of the voltage across the resistor:

Add their uncorrelated contributions:

+
$$V_R$$

$$\operatorname{var}(V_R) = \overline{R_a}^2 \sigma_{I_a}^2 + \overline{I_a}^2 \sigma_{R_a}^2$$

Standard deviation of the voltage across the resistor:

$$\sigma_{V_R} = \sqrt{\overline{R_a}^2 \sigma_{I_a}^2 + \overline{I_a}^2 \sigma_{R_a}^2}$$

Influence of supply and resistor tolerances



$$\frac{R_b}{R_a + R_b}$$

$$\sqrt{\left(\frac{R_a}{R_a+R_b}\right)^2 \left(\sigma_2^2 + \sigma_3^2\right) + \sigma_1^2}$$

Influence of controller biasing errors

SLiCAP model of ideal OpAmp with bias errors

- Correlated bias currents
- Uncorrelated offsets



Total bias errors



Simplified result: $R_c \gg \frac{R_a R_b}{R_a + R_b}$

$$= 2\sigma_r^2 \left(\frac{V_s}{R_a + R_b}\right)^2 \left(\frac{R_a R_b}{R_a + R_b}\right)^2$$

+ $\sigma_v^2 V_s^2 \left(\frac{R_b}{R_a + R_b}\right)^2$
+ v_{off}^2
+ $v_{off}^2 (R_c + 19R)^2$
+ $\sigma_{Ib}^2 I_b^2 (R_c - 19R)^2$
+ $\sigma_r^2 I_b^2 \left(R_c^2 + (19R)^2\right)$